

N-Ch MOSFET

General Description

The WSF3038 is the highest performance trench N-ch MOSFETs with extreme high cell density , which provide excellent R_{DSON} and gate charge for most of the synchronous buck converter applications .

The WSF3038 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Product Summery

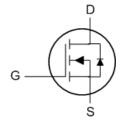
BVDSS	RDSON	ID
30V	15mΩ	38A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

TO-252 Pin Configuration





Absolute Maximum Ratings

Symbol	Parameter Rating		Units	
V_{DS}	Drain-Source Voltage	30	V	
V_{GS}	Gate-Source Voltage ± 20			
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 10V ¹ 38			
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹ 18			
I _{DM}	Pulsed Drain Current ² 60		А	
EAS	Single Pulse Avalanche Energy ³ 72		mJ	
I _{AS}	Avalanche Current 21		Α	
P _D @T _C =25℃	Total Power Dissipation ⁴ 25		W	
T _{STG}	Storage Temperature Range -55 to 150		$^{\circ}$	
T_J	Operating Junction Temperature Range -55 to 150			

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient (<10s) ¹		25	°C/W
$R_{ heta JA}$	Thermal Resistance Junction-ambient (Steady State) ¹	62		°C/W
R _{eJC}	Thermal Resistance Junction-Case ¹		5	°C/W





Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25℃ , I _D =1mA		0.023		V/°C
D	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =10A		15	20	0
R _{DS(ON)}		V _{GS} =4.5V , I _D =5A		22	35	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	V _{GS} =V _{DS} . In =250uA	1.0	1.5	2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	VGS-VDS , ID -250UA		-5.2		mV/℃
	Drain Source Leakage Current	V_{DS} =24V , V_{GS} =0V , T_J =25 $^{\circ}$ C			1	uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =24V , V _{GS} =0V , T _J =55°C			5	
I _{GSS}	Gate-Source Leakage Current	V_{GS} = $\pm 20V$, V_{DS} = $0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =15V , I _D =10A		10		S
Rg	Gate Resistance	V _{DS} =24V , V _{GS} =0V , f=1MHz		2.5		Ω
Q_g	Total Gate Charge (4.5V)	V _{DS=} 20V , V _{GS} =4.5V , I _D =10A		7.2		
Q_gs	Gate-Source Charge			1.4		nC
Q_gd	Gate-Drain Charge			2.6		
T _{d(on)}	Turn-On Delay Time	V_{DD} =12V , V_{GS} =10V , R_{G} =3.3 Ω , I_{D} =5A		4.1		
T _r	Rise Time			9.8		no
$T_{d(off)}$	Turn-Off Delay Time			22		ns
T _f	Fall Time			6.0		
Ciss	Input Capacitance	V _{DS} =25V , V _{GS} =0V , f=1MHz		550		
C _{oss}	Output Capacitance			68		pF
C _{rss}	Reverse Transfer Capacitance			55		

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.1mH , I _{AS} =10A	16			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,6}	V _G =V _D =0V , Force Current			10	Α
I _{SM}	Pulsed Source Current ^{2,6}				60	Α
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =15A , T _j =25℃			1.2	V

Note:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.
- 2. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- 3. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V, L=0.1mH, I_{AS} =10A
- 4. The power dissipation is limited by 150 °C junction temperature
- 5. The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



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Typical Characteristics

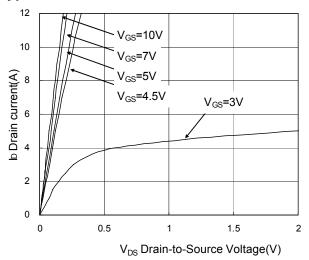


Fig.1 Typical Output Characteristics

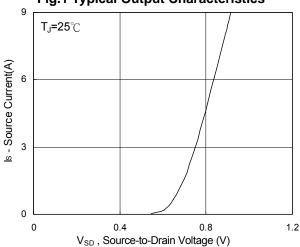
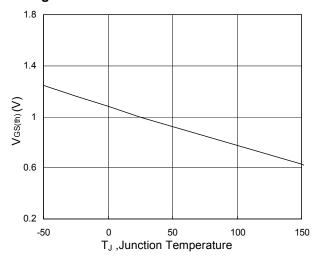


Fig.3 Forward characteristics of reverse



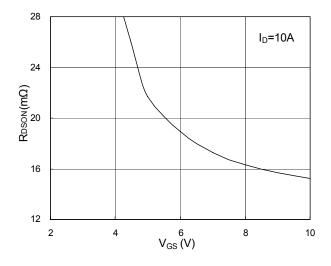


Fig.2 On-Resistance vs. G-S Voltage

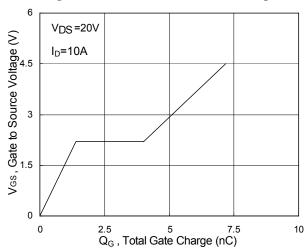


Fig.4 Gate-charge characteristics

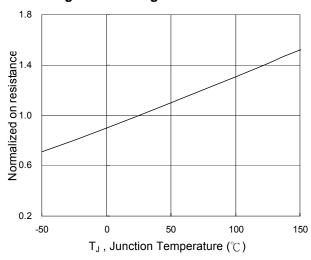
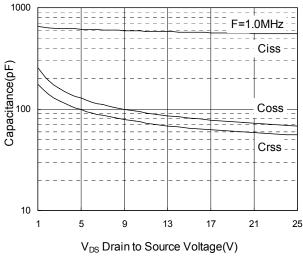


Fig.6 Normalized R_{DSON} vs. T_J

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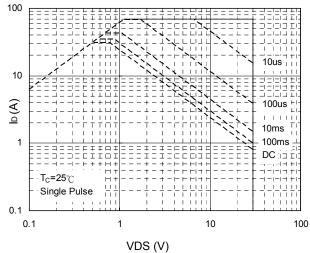


Fig.7 Capacitance

Fig.8 Safe operating area

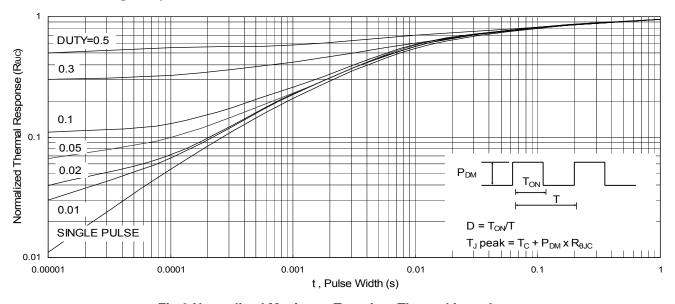
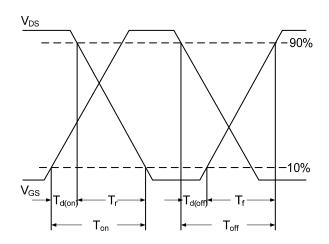


Fig.9 Normalized Maximum Transient Thermal Impedance



 $EAS = \frac{1}{2} L \times I_{AS}^{2} \times \frac{BV_{DSS}}{BV_{DSS}} - V_{DD}$ $BV_{DSS} - V_{DD} = V_{DD}$ $V_{DD} = V_{DS}$ $V_{GS} = V_{DS}$

Fig.10 Switching time waveform

Fig.11 Unclamped inductive switching wave.



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